

<b>Notice of References Cited</b>	Application/Control No. 10/573,536		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner GREG BENGZON		Art Unit 2444	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0220926 A1	11-2004	Lamkin et al.	707/003
*	B	US-2004/0220791 A1	11-2004	Lamkin et al.	703/011
*	C	US-2003/0229900 A1	12-2003	Reisman, Richard	725/87
*	D	US-2005/0267994 A1	12-2005	Wong et al.	709/246
*	E	US-2002/0143901 A1	10-2002	Lupo et al.	709/219
*	F	US-7,434,247 B2	10-2008	Dudkiewicz et al.	725/46
*	G	US-7,055,168 B1	05-2006	Errico et al.	725/46
*	H	US-2003/0061610 A1	03-2003	Errico, James H.	725/46
*	I	US-2008/0028101 A1	01-2008	Dewa, Yoshiharu	709/246
*	J	US-7,359,955 B2	04-2008	Menon et al.	709/219
*	K	US-2004/0267805 A1	12-2004	Sezan et al.	707/102
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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